

EAST


10/723,905

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	505	test\$3 and (voltage or current or power) and (ic or integrated adj circuit or die) and (record\$3 or memory or memories or storage) and reference and (time or timing) and (numerical or quantitative or (logic or logical) adj output).clm.	US-PGPUB	OR	ON	2005/07/07 17:49 <i>RK</i>

*Interference Search History*

EAST

10/723,905

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	439	326/16.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 16:48
L2	253	1 and (record\$3 or storage or storing or stored or memory or memories)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 16:49
S1	1	("6177786").PN.	USPAT	OR	OFF	2005/07/07 14:55
S2	1	on adj chip and voltage with (power adj supply or regulat\$3) and (time or timing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/06 16:02
S3	5572	on-chip and voltage with (power adj supply or regulat\$3) and (time or timing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/06 16:02
S4	175	S3 and "714"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/06 16:02
S5	2384	714/25,733.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 14:57
S6	1955	S5 and (test\$3 or measur\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 15:05
S7	1555	S6 and (record\$3 or storage or storing or stored or memory or memories)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 15:06 

EAST

10/723,905

S8	176	S7 and (time or timing) with (reference)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 15:06
S9	5528	324/158.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 15:05
S10	4430	S9 and (test\$3 or measur\$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 15:05
S11	1653	S10 and (record\$3 or storage or storing or stored or memory or memories)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 16:49
S12	200	S11 and (time or timing) with (reference)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 15:07
S13	140	S12 and (chip or integrated adj circuit or die or wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/07 16:47  RK